



(PHIL) Simulation based Testing

Solar PV Inverter Islanding and Medium Voltage DC Systems

May 2015

Mischa Steurer, James Langston, John Hauer, Ferenc Bogdan, Michael Murry, Karl Schoder

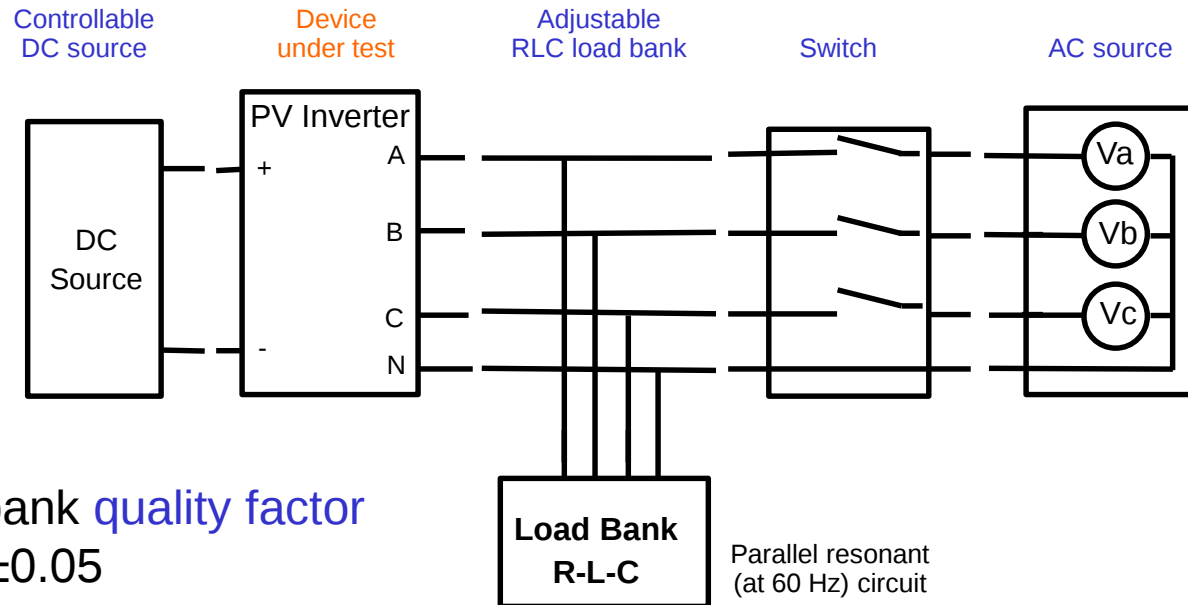
Dionne Soto, Matthew Bosworth



RTDS Users' Group Meeting
San Francisco, CA

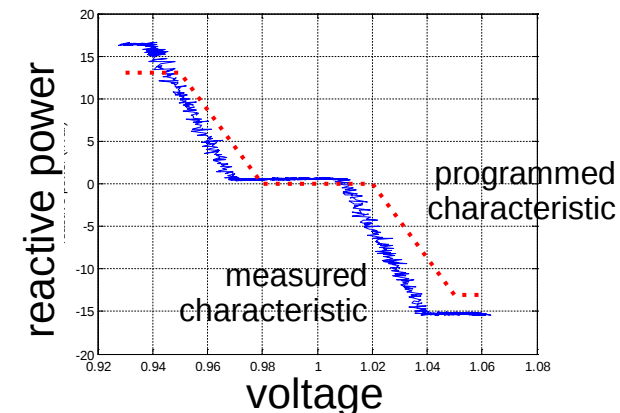


Unintentional Islanding Test (IEEE 1547.1)



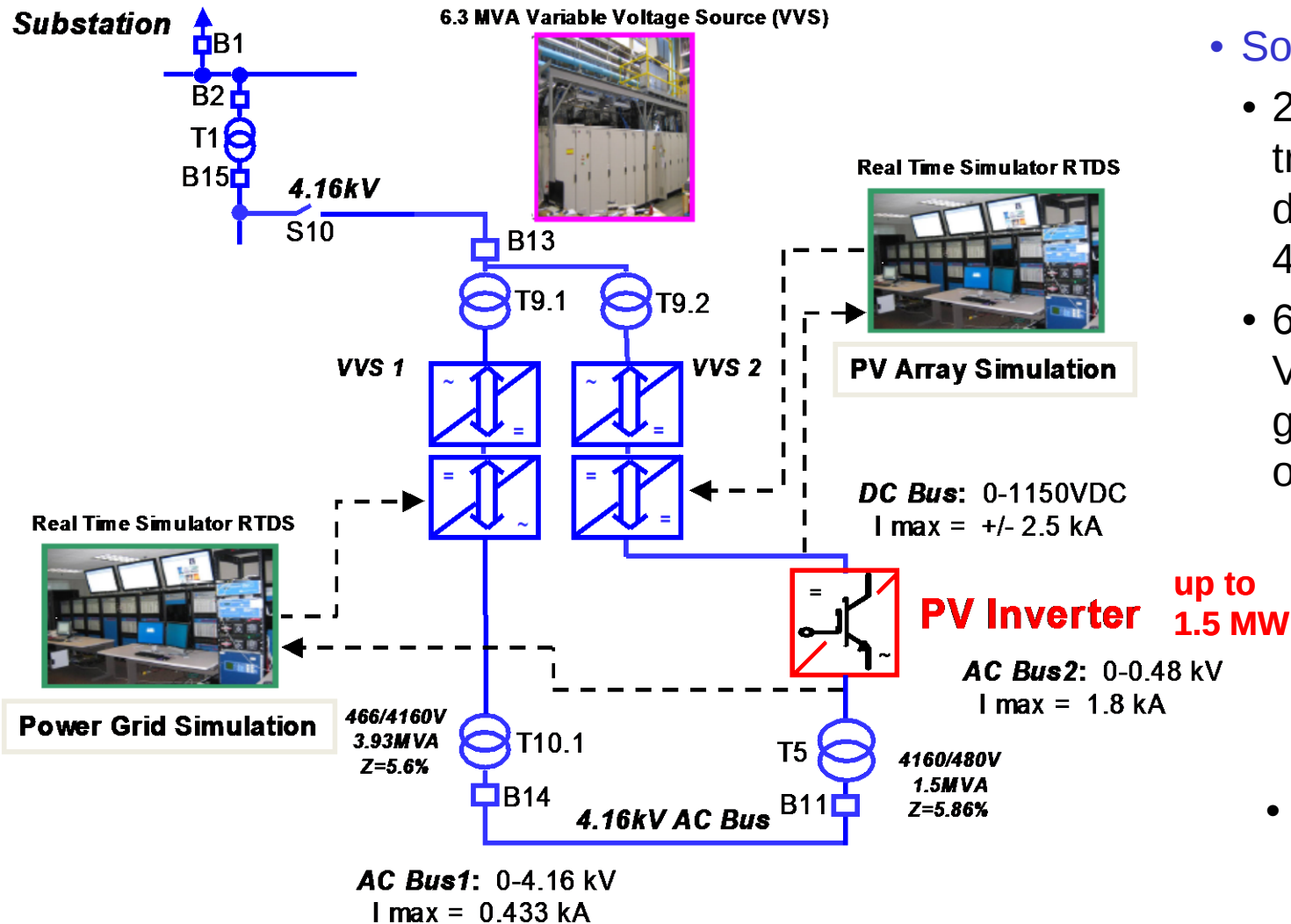
Part of Hi-Pen PV
Integration Project,
Barry Mather

- Load bank **quality factor**
 $Q_f = 1 \pm 0.05$
- Residual current from grid:
Inverter output matches load active power
- Inverter has **2 seconds to detect** island (tries to destabilize system)
- Issues
 - Costs, inflexible, time (test setup reconfiguration)
 - What if advance control functions are active?
 - Can PHIL approach be used?



Test Setup and Facilities

Substation

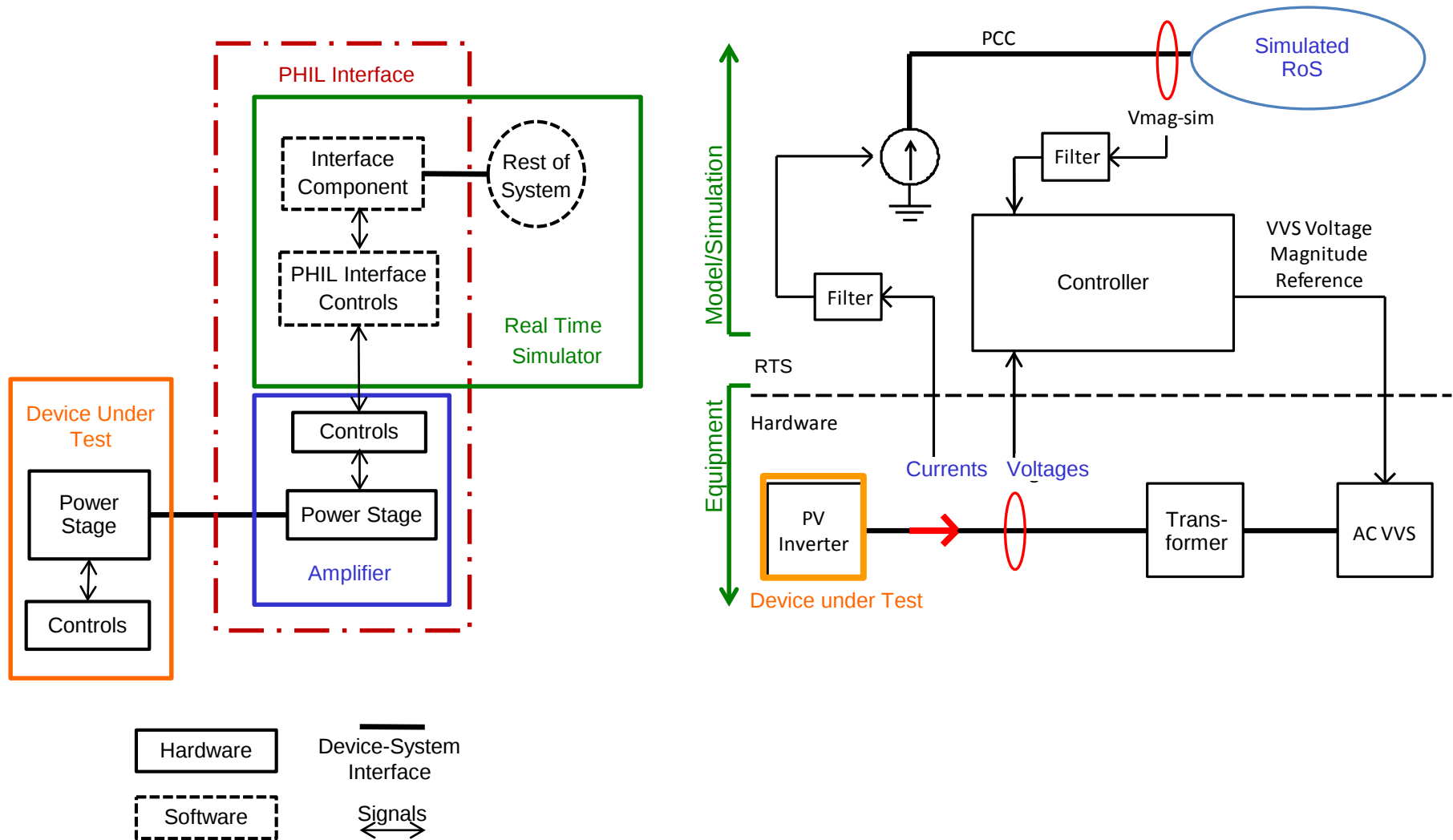


- Solar PV inverters
 - 20 kW, transformerless design, 480 V/277 V wye
 - 60 kW, 480 V/277 V wye with galvanic isolation on DC side
- Linear amplifier, limited to 350Vdc and 10 kW

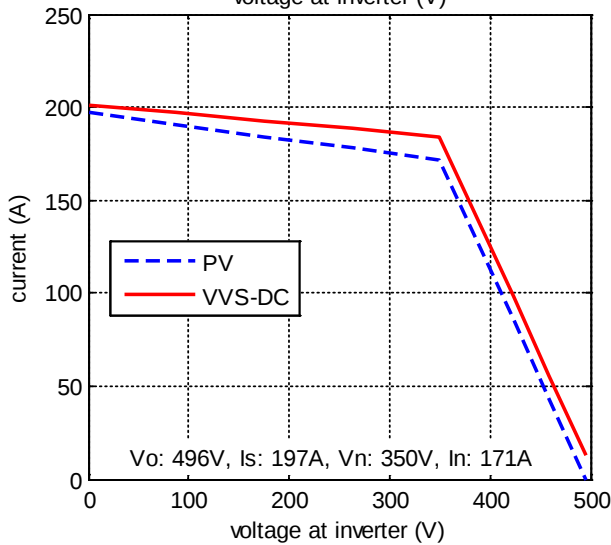
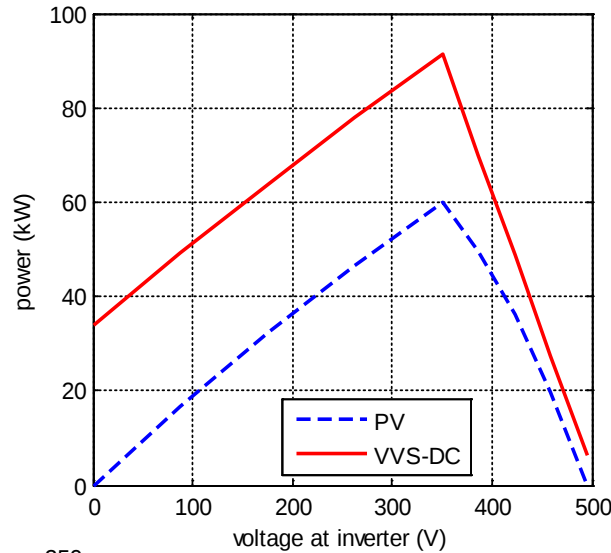
Power Hardware-in-the-Loop

Simulation Principle

Coupling simulation and hardware



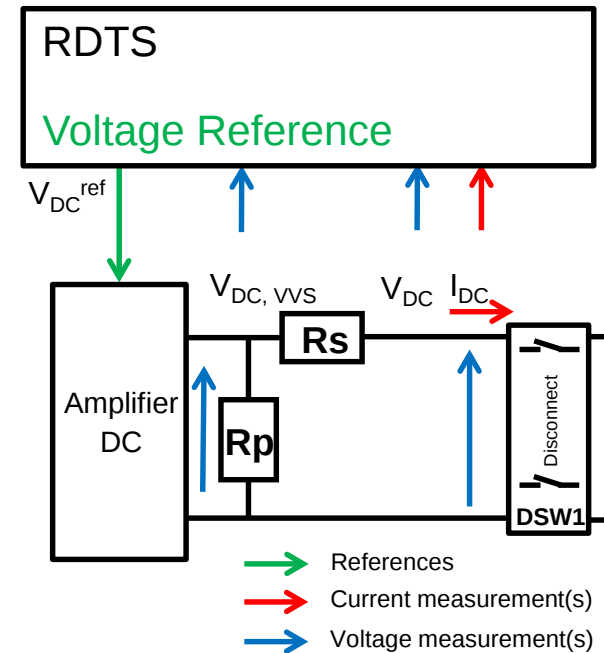
Emulating Solar PV Arrays



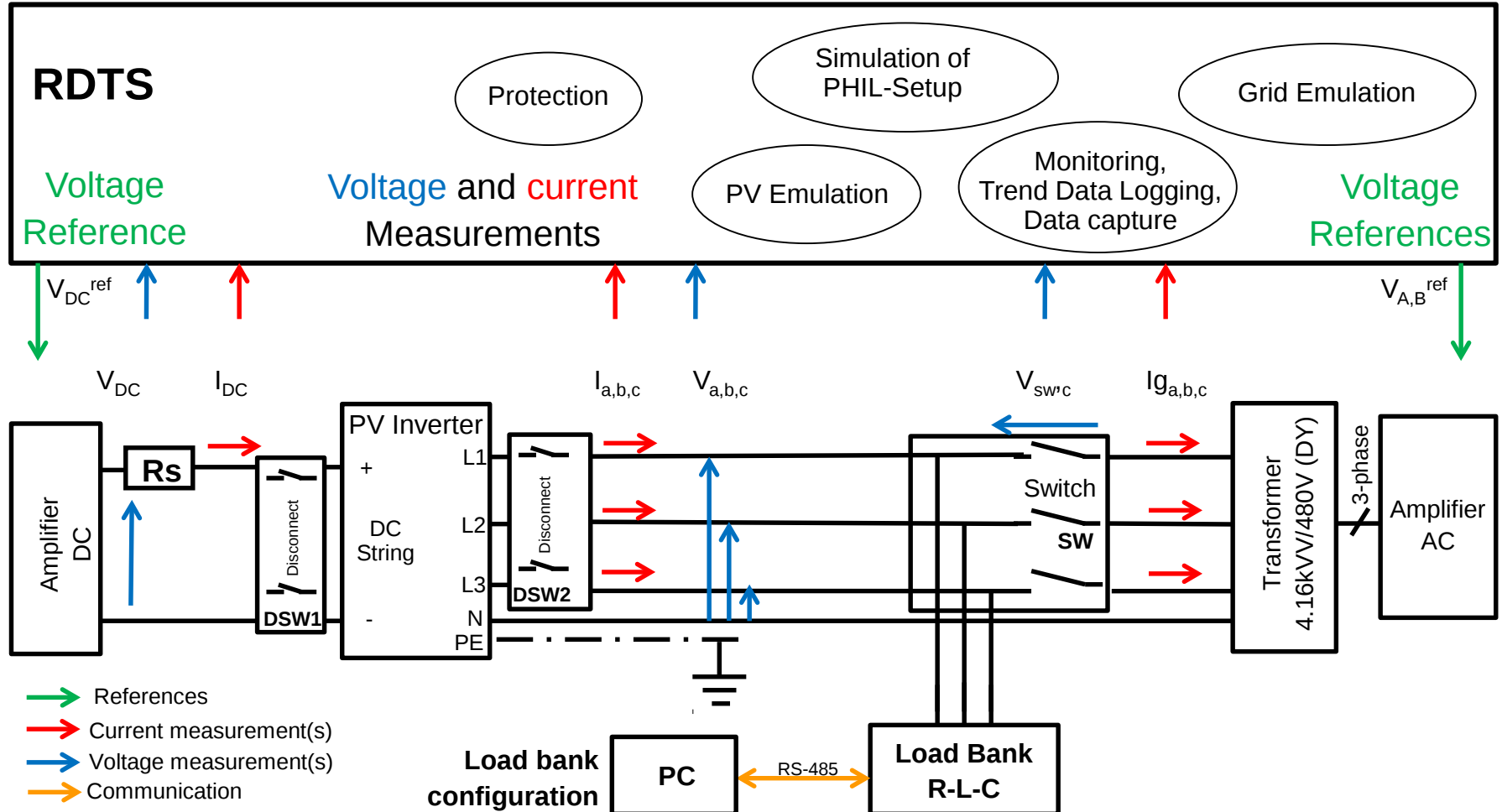
- PV array characteristic (blue)
- Amplifier control characteristic (red)

PHIL-interface on DC-side

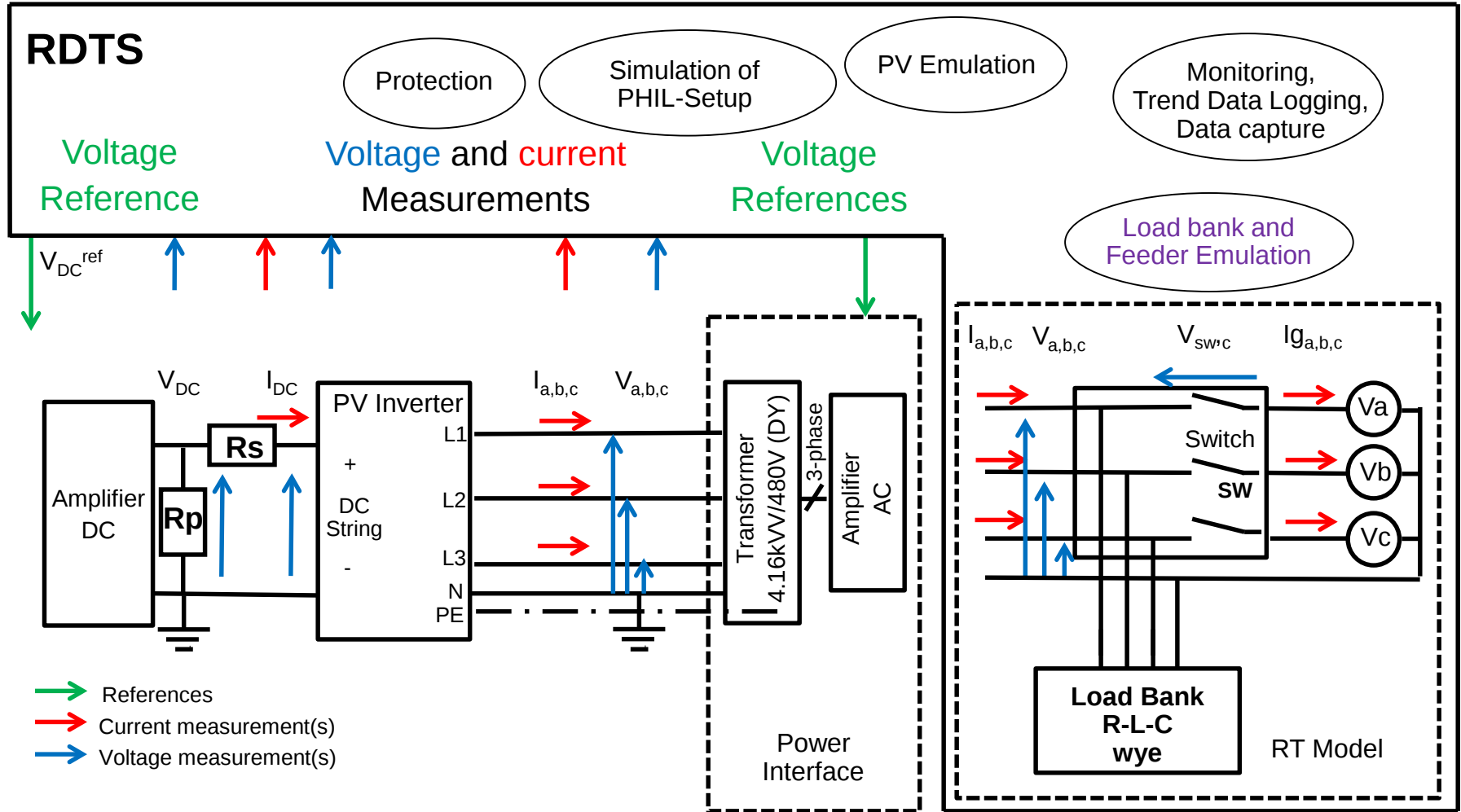
- Instantaneous voltage and current



Test Setup with Load Bank



Test Setup for PHIL





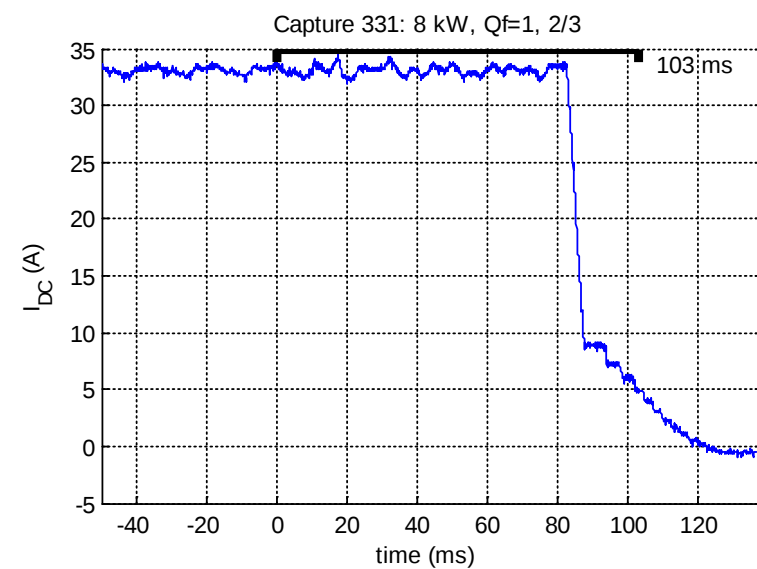
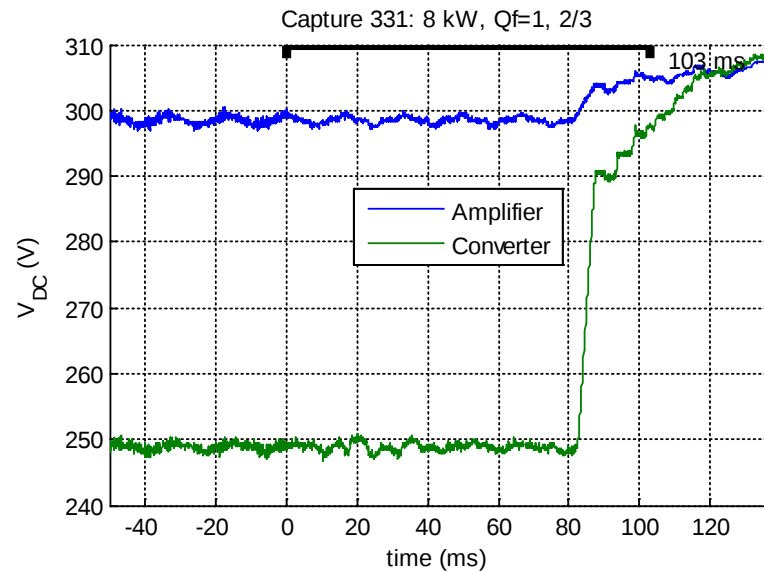
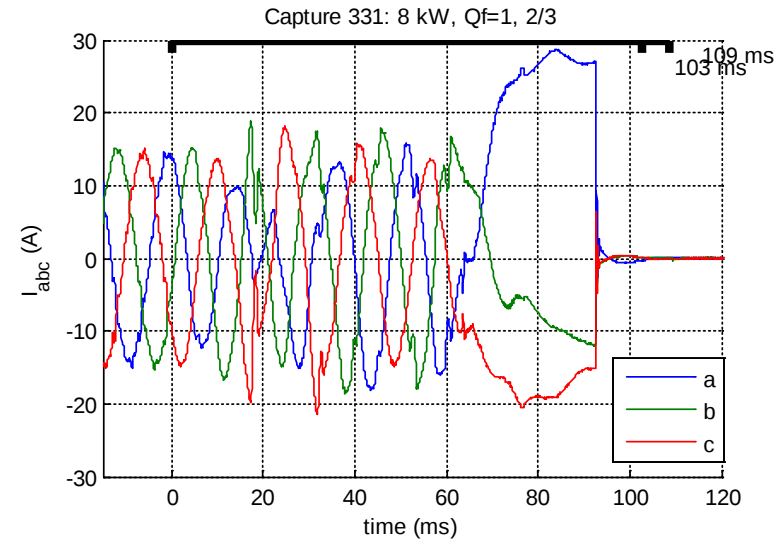
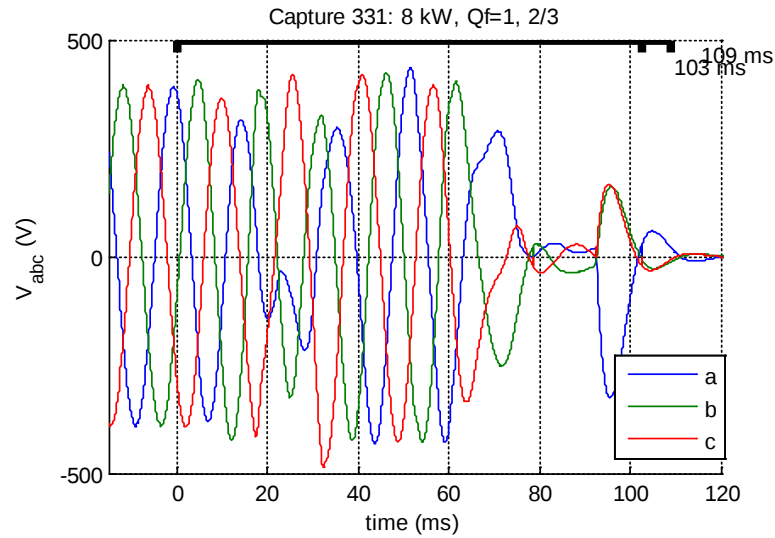
PHIL Interface Algorithms



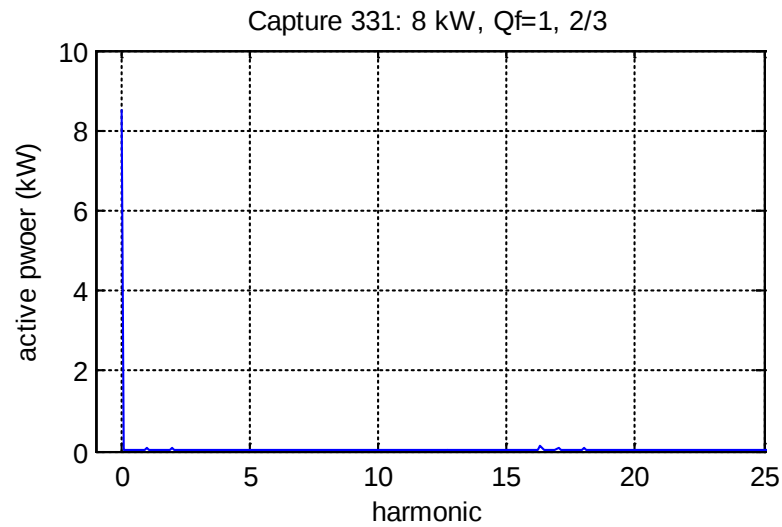
Several PHIL interface algorithms available and used:

- Reference frame based approaches
 - Positive and negative sequence tracking
- Instantaneous Ideal Transformer Model (ITM)
 - Simple from an implementation standpoint
 - Region of stability smaller than compared to DIM
- Instantaneous Damping Impedance Method (DIM)
 - Current and voltage fed back into Rest-of-System model
- Challenges
 - Time delays
 - Stability and accuracy

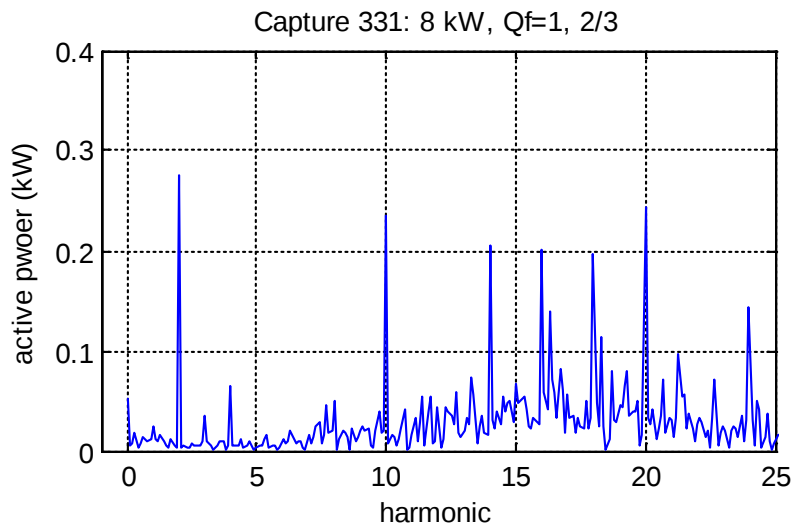
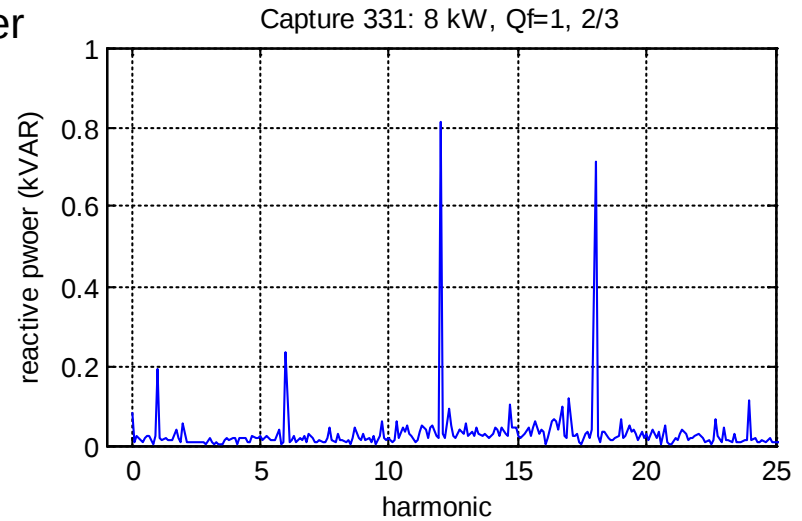
Example Results: Using Load Bank (baseline)



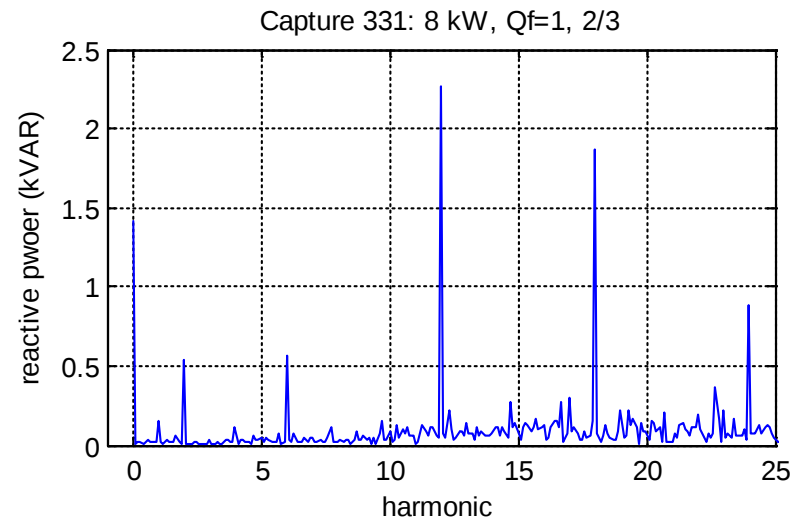
Example Results: Using Load Bank



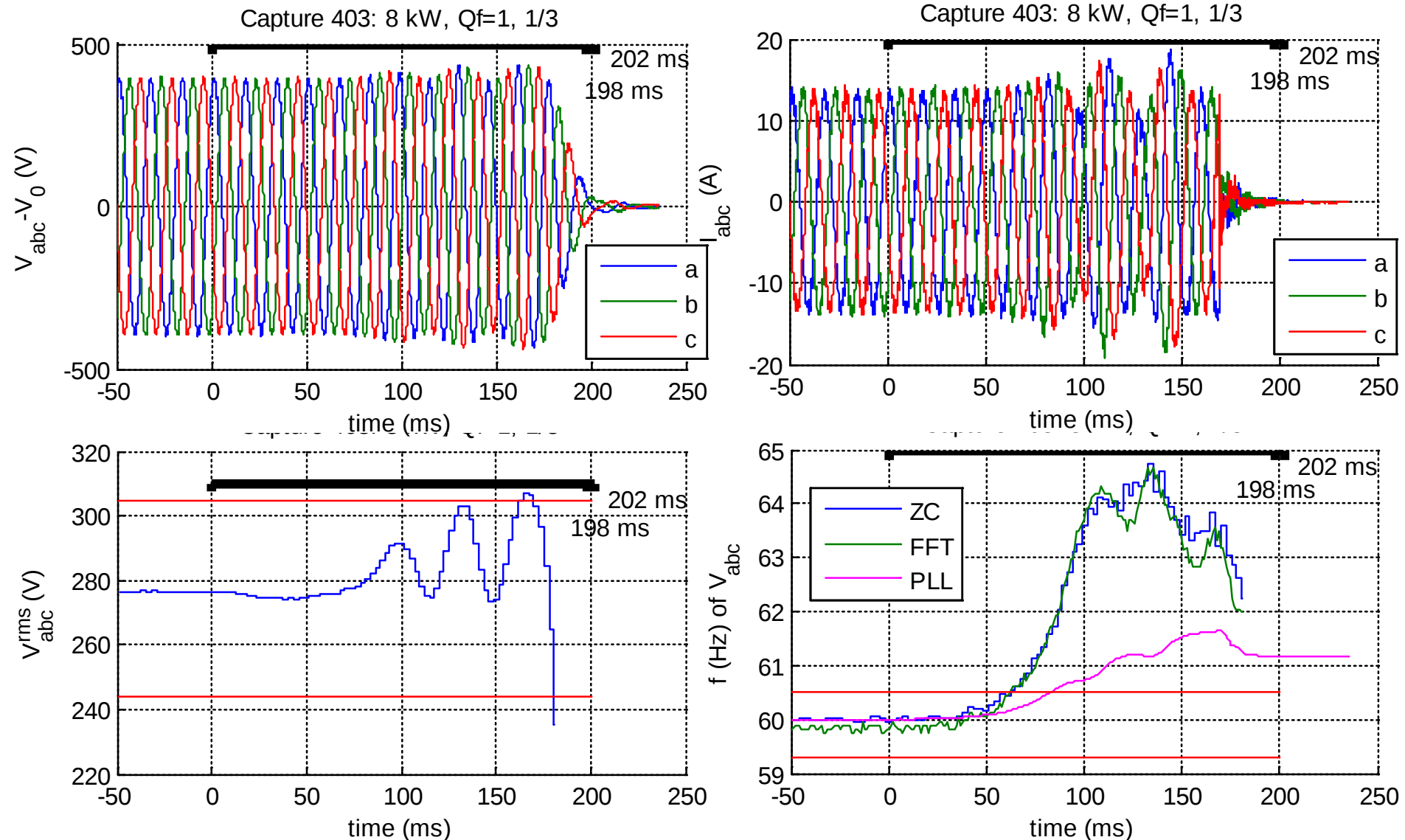
Inverter



Grid

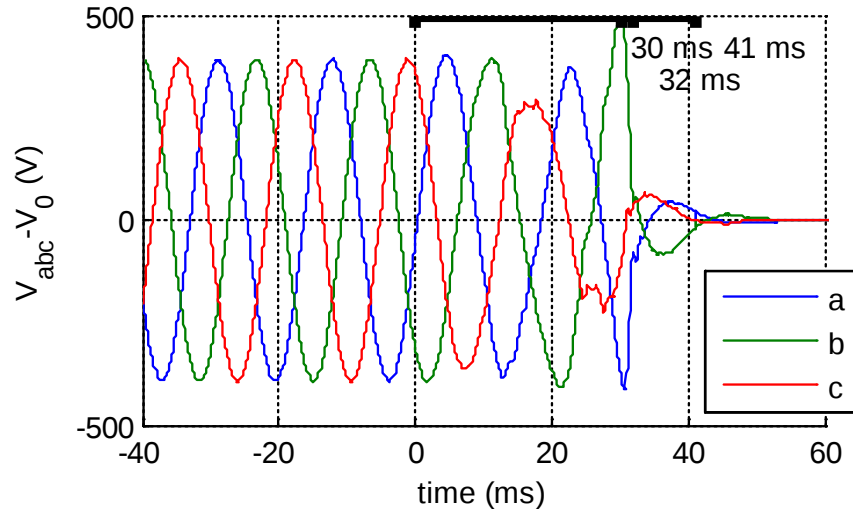


Example Results: RLC with DQ-PHIL

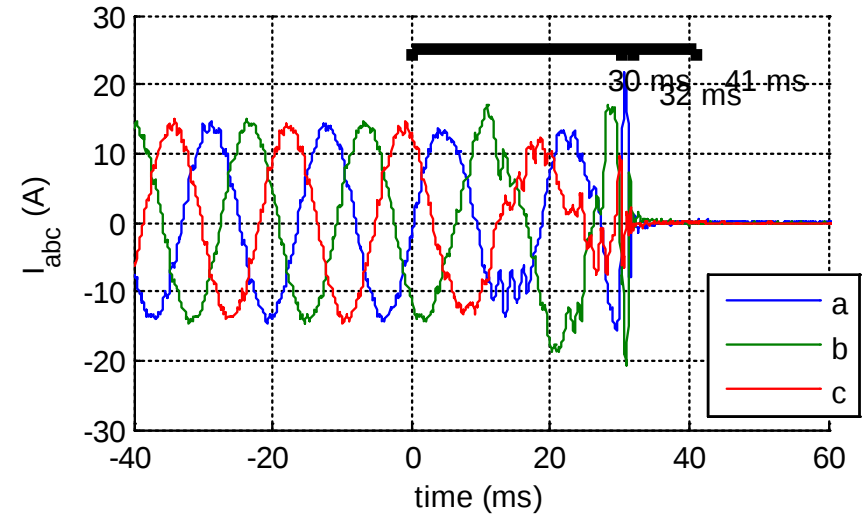


Example Results: RLC with ITM-PHIL

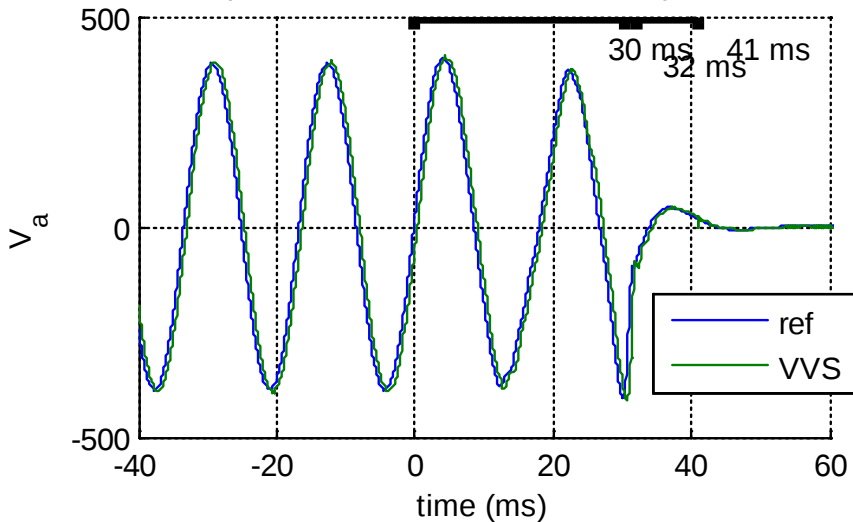
Capture 563: 8 kW, $Q_f=1$, ITM, R_{wye}, 2/10



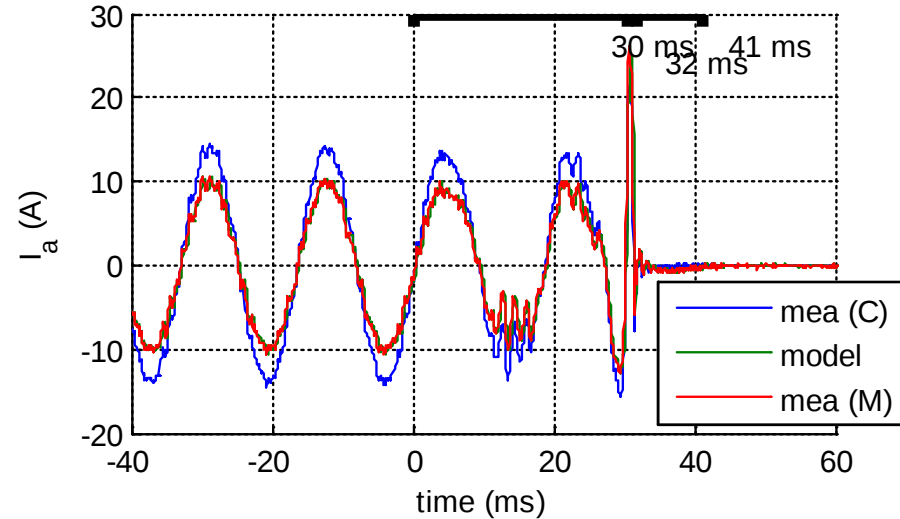
Capture 563: 8 kW, $Q_f=1$, ITM, R_{wye}, 2/10



Capture 563: 8 kW, $Q_f=1$, ITM, R_{wye}, 2/10

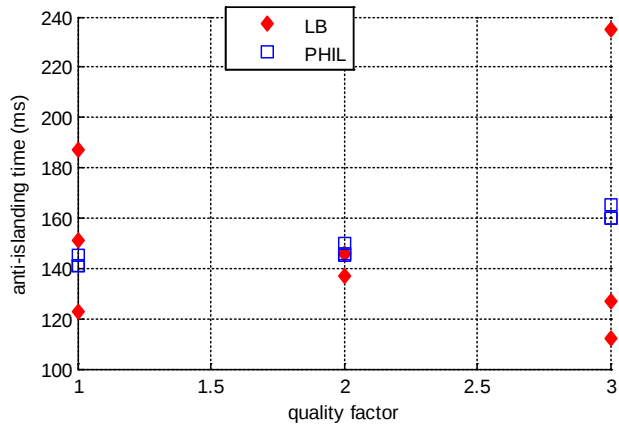


Capture 563: 8 kW, $Q_f=1$, ITM, R_{wye}, 2/10

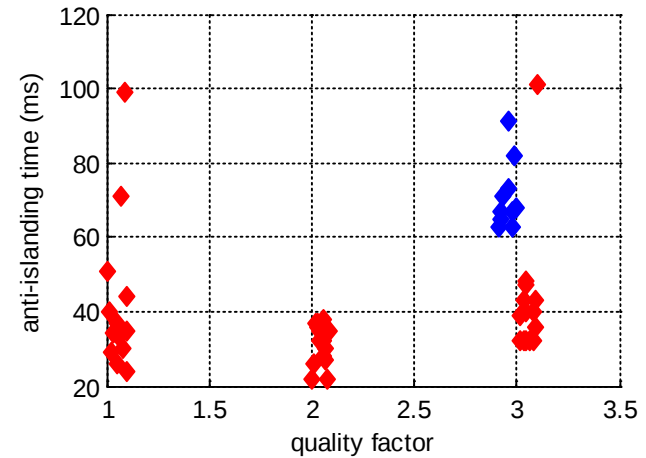


Timing for RLC Load Bank

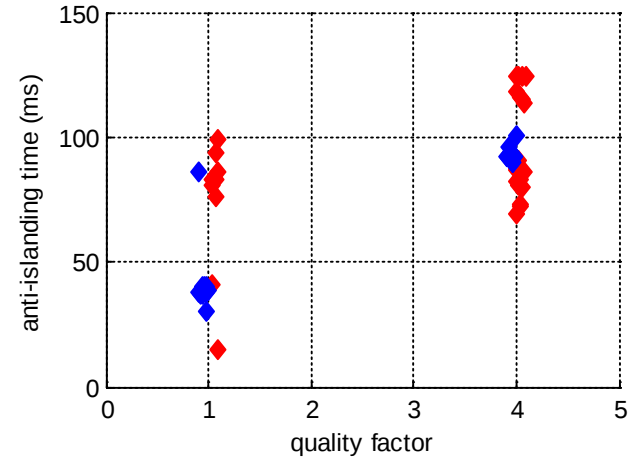
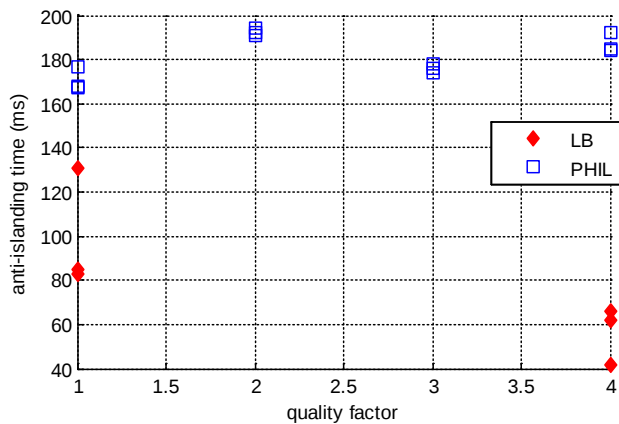
3 kW Load bank vs. DQ-PHIL



Load bank vs. ITM-PHIL



8 kW

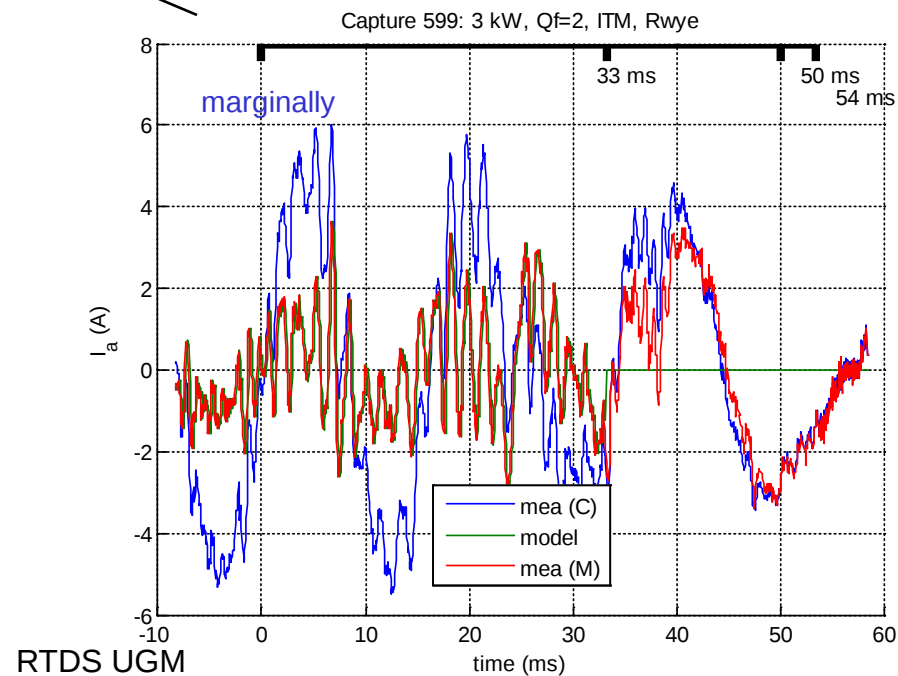
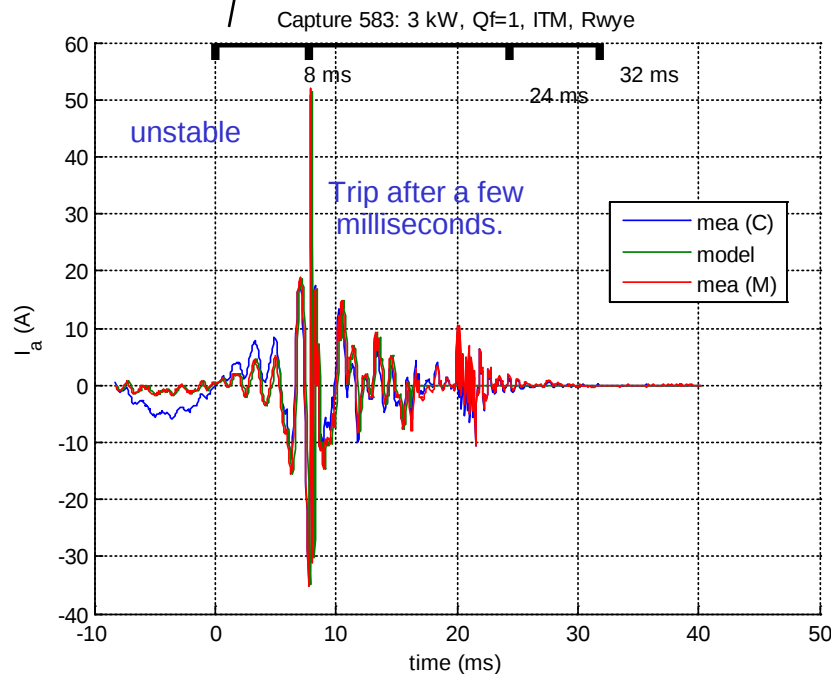
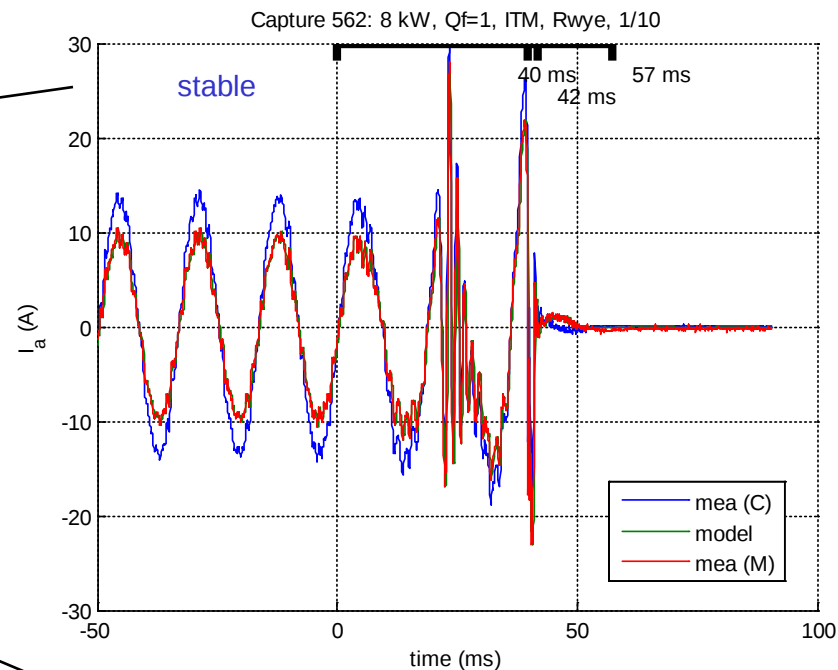
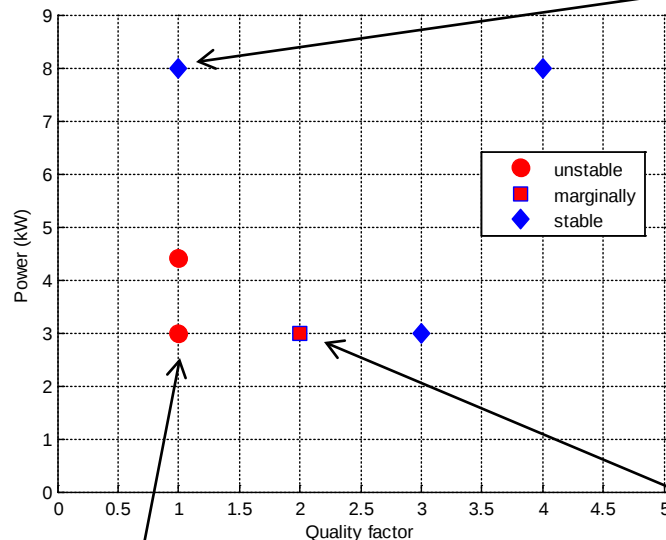


(Detection based on I_{DC})

Objective: PHIL-result pattern similar to load bank derived results.

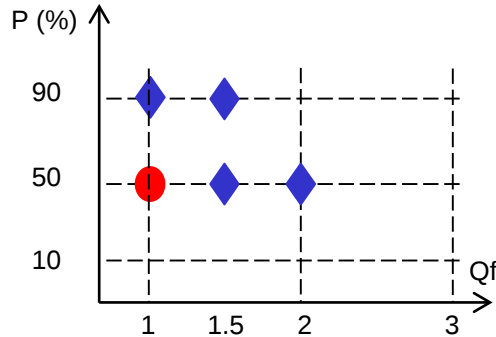


Example Traces: ITM-PHIL Stability

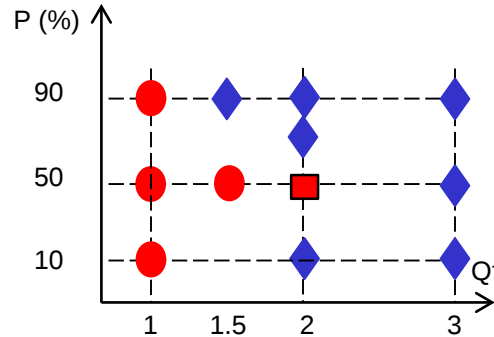


RTDS UGM

RLC Load bank: DIM

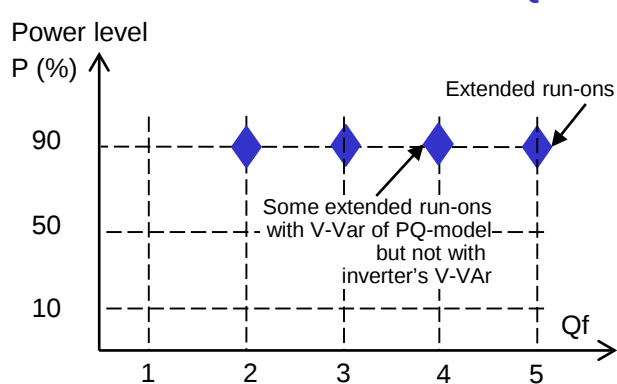


RLC Load Bank: ITM

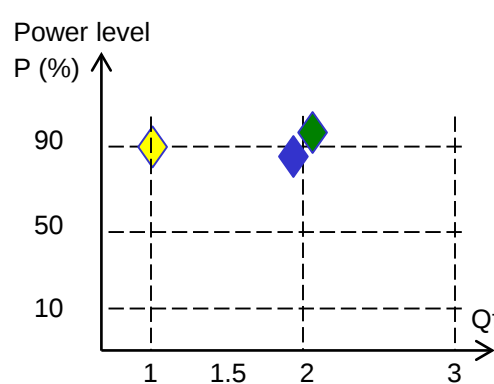


- Conditions beyond RLC load bank tested
- Flexibility of PHIL a clear benefit
- Inverters ability to detect islands when using PHIL maintained
- Need to get more robust at lower quality factors (stability an issue)
- Testing will become more challenging (in number/costs) with new advanced functions: PHIL may reduce costs

RLC-LB and Constant-PQ: ITM



Induction motor

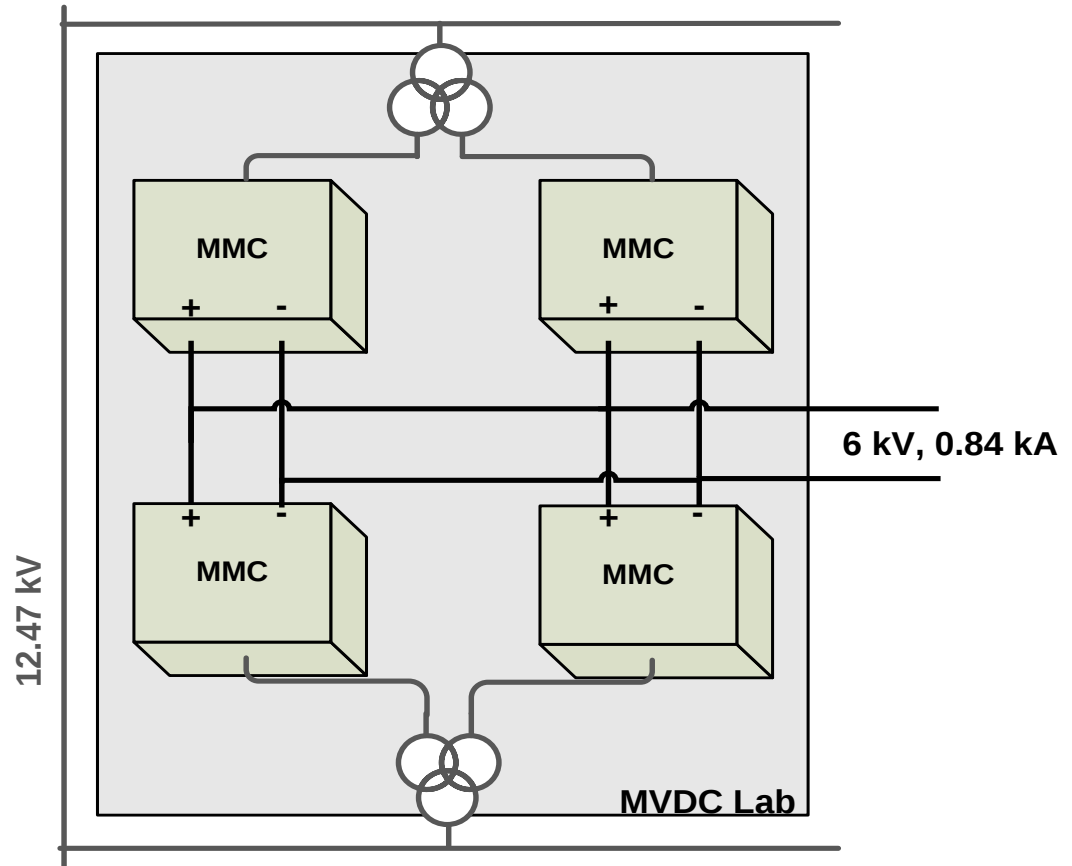


◆ ... stable ● ... unstable ■ ... marginally

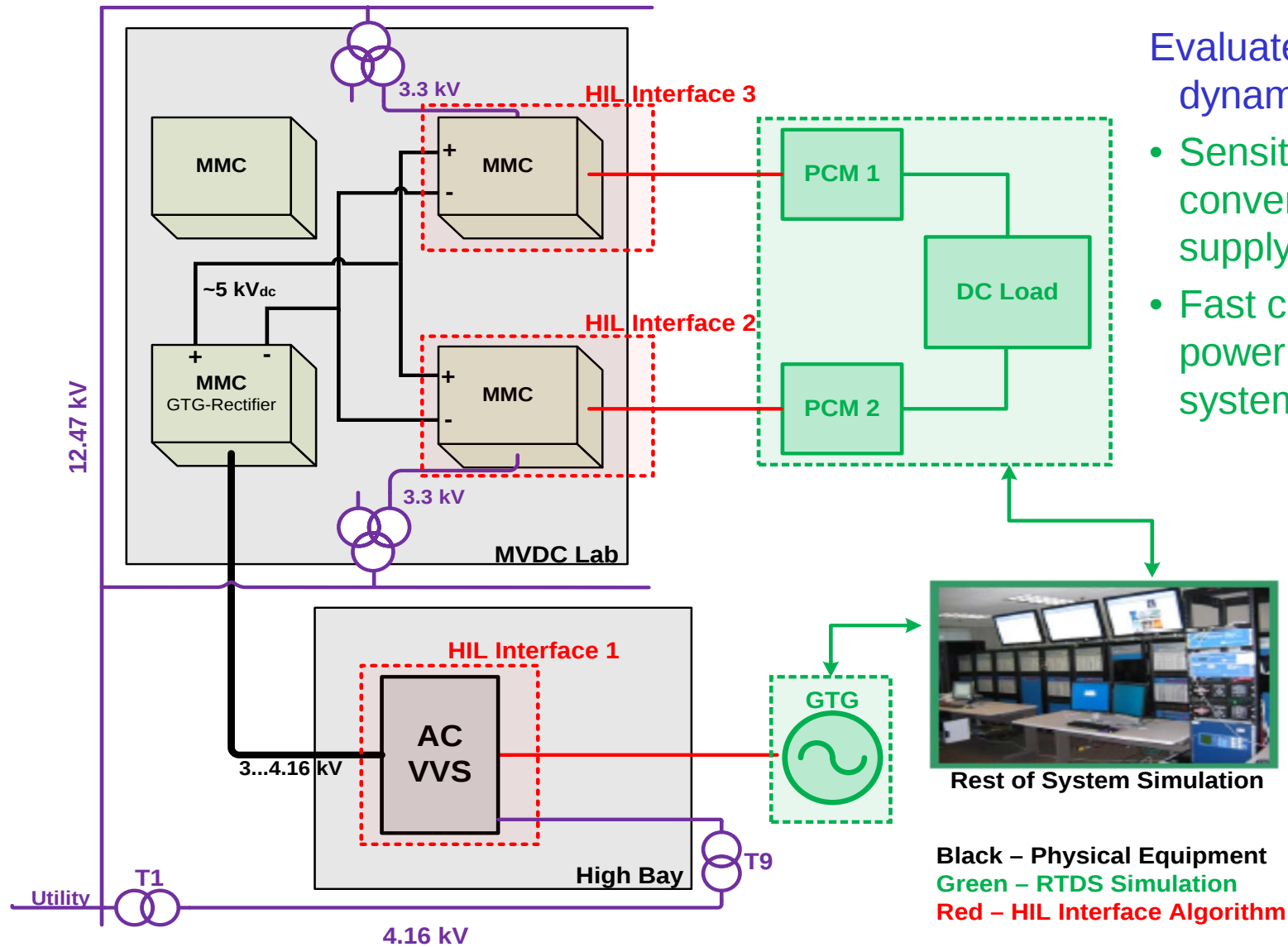
◆ stable ITM, island not detected ($S_N=221\text{kVA}$)
 ◆ stable ITM ($S_N=60\text{kVA}$)
 ◆ stable DIM before turn-off ($S_N=60\text{kVA}$)

New test facility at CAPS.

- Four Modular Multi-level Converters
- Operating modes
 - individual (6 kV, 210 A)
 - series (24 kV)
 - parallel (840 A)
 - back-to-back
- Controllable from RTDS
- Application: DC microgrids



A Test Application Example



Evaluate interacting dynamic systems.

- Sensitivity of converters to AC supply deviations.
- Fast changes in power within DC system.

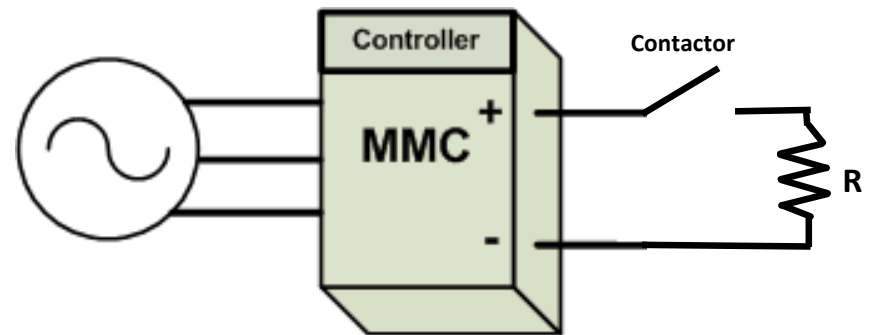
MVDC Fault Testing

Power electronics provide new means for fault handling:

- Controlled currents
- Interrupt in micro and milliseconds

Issues

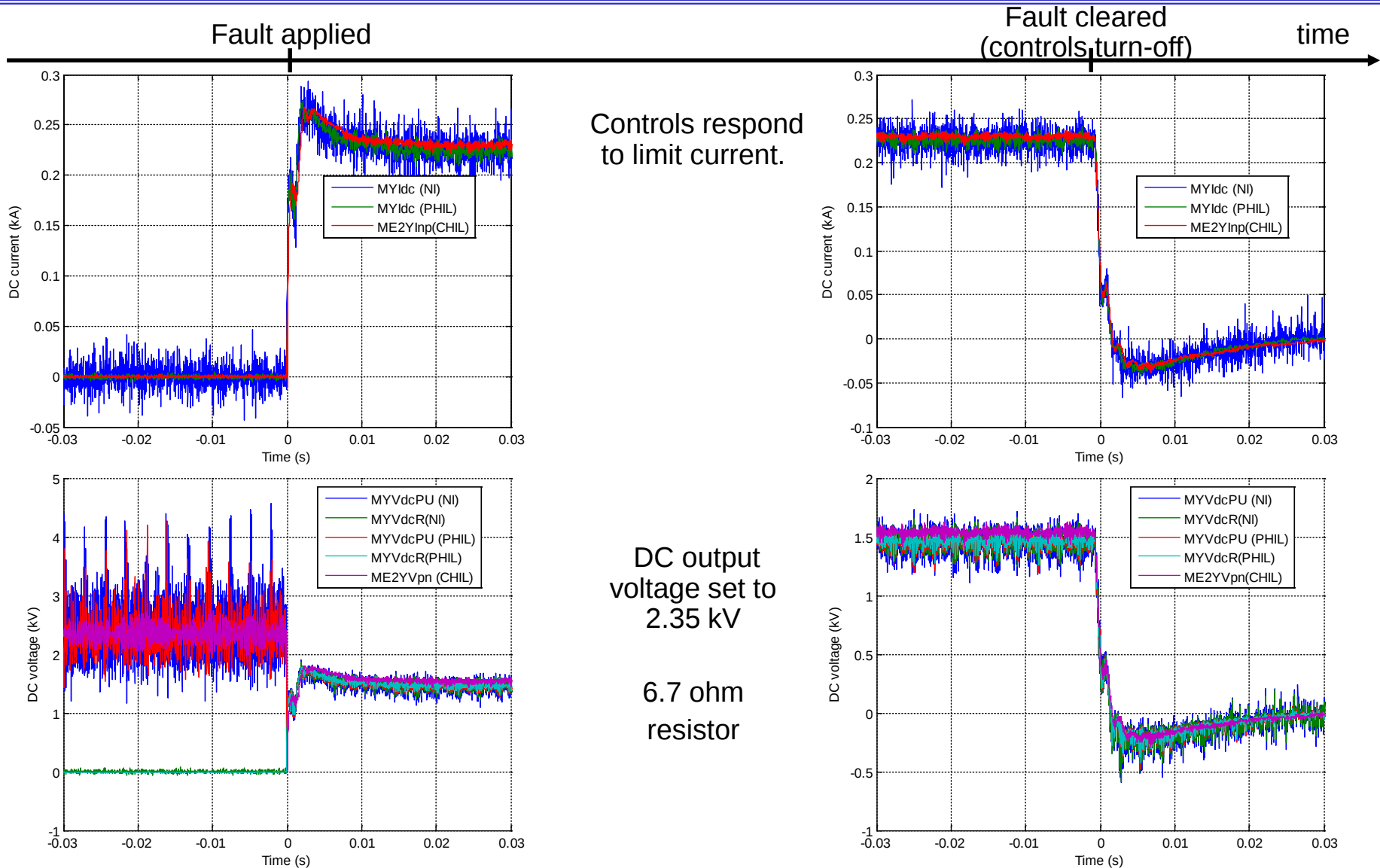
- Fault behavior
- Coordination



**Example test arrangement:
Closing a contactor into a Resistor**

MVDC Fault Testing

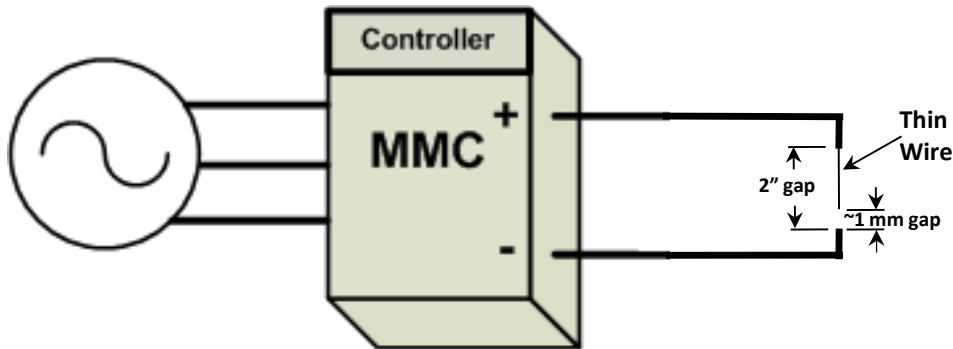
Logic implemented in RTDS to drop the DC voltage **300ms** after closing the contactor.



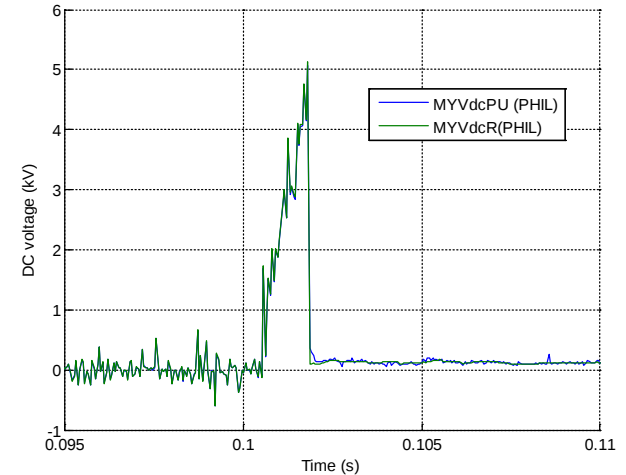
Arc Fault on DC Contacts with 2" Gap

Logic implemented in RTDS to step DC voltage from **0 to 5.5kV** and **back to 0V after 200ms**.

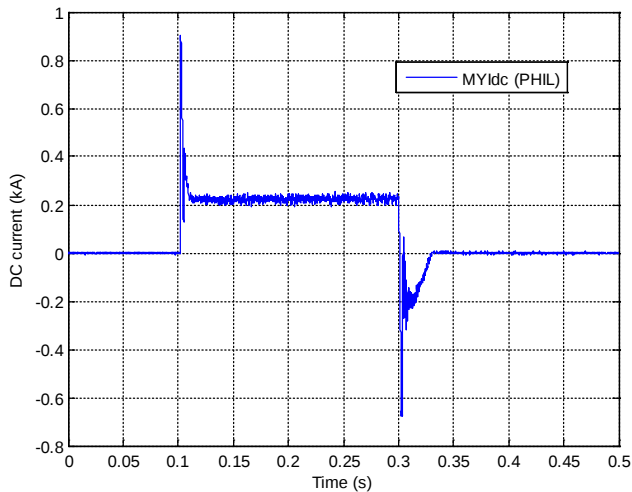
Arc fault setup with 2 inch gap between DC Rails and 1 mm gap between thin wire and negative DC Rail.



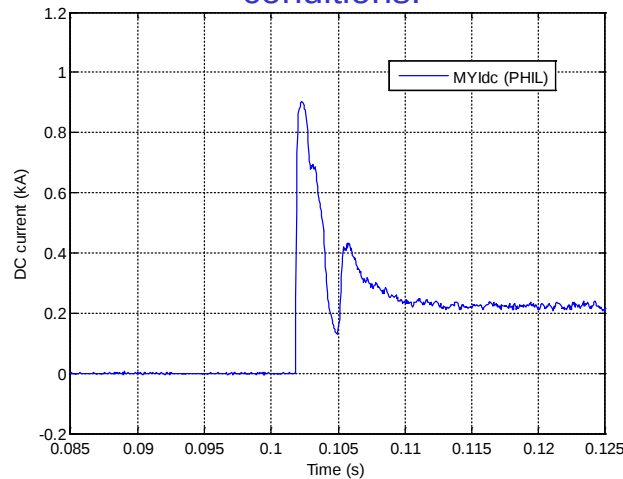
Voltage at beginning of fault condition.



Current during fault conditions.



Current at beginning of fault conditions.



Current at end of fault conditions.

